

Sheet 1 of 2

INFORMATION DISCLOSURE CITATION

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SERIAL NO.

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FILING DATE

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(Use several sheets if necessary)

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TC/A.U.

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U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

DOCUMENT		DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
	1 351 939	05/1974	GB				
	55 139643	10/1980	JP			ABSTRACT	
	59-22250	02/1984	JP			ABSTRACT	
	63-001175	01/1988	JP			ABSTRACT	
	06-267122	09/1994	JP			ABSTRACT	
	08-212604	08/1996	JP				
	09-097457	04/1997	JP			ABSTRACT	
	09-153235	06/1997	JP			ABSTRACT	
	09-222430	08/1997	JP			ABSTRACT	
	10-334525	12/1998	JP			ABSTRACT	
	11-045467	02/1999	JP			ABSTRACT	
	11-176033	07/1999	JP			ABSTRACT	
	1 333 436	08/2003	EP				
	1 369 864	12/2003	EP				
	1 381 042	01/2004	EP				
	1 398 779	03/2004	EP				
	1 398 780	03/2004	EP				

***Examiner**

Date Considered

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Sheet 1 of 2

INFORMATION DISCLOSURE CITATION	ATTY. DOCKET NO.	SERIAL NO.
	4105-74	10/568,943
	APPLICANT	
(Use several sheets if necessary)	CHO et al.	
	FILING DATE	TC/A.U.
	March 22, 2006	2627

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U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

SEARCHED DOCUMENTS						TRANSLATION	
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	1 351 939	05/1974	GB				
	55 139643	10/1980	JP			ABSTRACT	
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	1 381 042	01/2004	EP				
	1 398 779	03/2004	EP				
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		<u>CHO et al.</u>	
(Use several sheets if necessary)		FILING DATE	TC/A.U.
		<u>March 22, 2006</u>	<u>2627</u>

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

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